



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: TB1410-02 DATE: 4-Nov-2014 Product Affected: 4DB0124KB1AVG 4DB0124KB1AVG8 4DB0124KB1AVG8/M Date Effective: 4-Feb-2015	MEANS OF DISTINGUISHING CHANGED DEVICES: <input type="checkbox"/> Product Mark <input type="checkbox"/> Back Mark Traceability to the test location is <input type="checkbox"/> Date Code maintained by IDT and available on <input checked="" type="checkbox"/> Other request
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Contact: IDT PCN DESK E-mail: pcndesk@idt.com	Attachment: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No Samples: Please contact your local sales representative for sample request.
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DESCRIPTION AND PURPOSE OF CHANGE:

<input type="checkbox"/> Die Technology <input type="checkbox"/> Wafer Fabrication Process <input type="checkbox"/> Assembly Process <input type="checkbox"/> Equipment <input type="checkbox"/> Material <input type="checkbox"/> Testing <input checked="" type="checkbox"/> Manufacturing Site <input type="checkbox"/> Data Sheet <input type="checkbox"/> Other	<p>This notification is to advise our customers that IDT is adding ASEK, Taiwan as an alternate facility for Test process for the selective products that are presently tested at IDT Penang, Malaysia facility. Products tested in ASEK will also complete the Backend process in this same facility.</p> <p>Attachment I details the change.</p>
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RELIABILITY/QUALIFICATION SUMMARY:

There is no expected change to the product quality or reliability performance. Please refer to Attachment I for Electrical correlation data.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.

IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> <i>Approval for shipments prior to effective date.</i>
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone# /Fax# : _____
CUSTOMER COMMENTS: _____	

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____



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PCN Type: Manufacturing Site - Alternate Test & Backend Location
Data Sheet Change: None
Detail Of Change:

This notification is to advise our customers that IDT is adding ASEK, Taiwan as an alternate facility for Test process for the selective products that are presently tested at IDT Penang, Malaysia facility. Products tested in ASEK will also complete the Backend process in this same facility.

This change will allow IDT the flexibility to ship from either facility and will provide the increased capacity, flexibility and shorter lead time to meet market demand.

There is no change in the Test processing flows. Tester configuration used at IDT Penang is the same as ASEK. IDT has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the test facilities with no change to the test coverage. The Backend process is standardized between the two sites. The carrier tape and plastic reel used in ASEK are with the same dimensions as used in IDT Penang. There is no change to form, fit and functions. Refer to Table 1 and Table 2 for the comparisons.

There is no change in the moisture sensitivity level (MSL).

If you require samples to conduct evaluations, please contact your local sales representative to acknowledge this PCN and request samples.



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Qualification Information and Qualification Data: Electrical Test Correlation Results

Vehicle: 4DB0124KB1AVG

Sample size: 1000 electrically good units and 40 reject units

Description	Existing Test (IDT, Penang)	Alternate Test (ASEK, Taiwan)
Tester Platform	V93000	V93000
Loadboard	SN#1	SN#1
Test Program	CK_SQB1_TF	CK_SQB1_TF
Test Site	8	8
Test Temperature	105°C	105°C
Test Correlation Results	100%	100%
Number of Good Units Correlated @ ambient	1000 pcs	1000 pcs
1000 units Bin 1 handler run (good units)	Passed	Passed
Number of Reject Units Correlated @ ambient	40 pcs	40 pcs
40 units rejects handler run	Passed	Passed
1000 units Bin 1 datalog correlation (good units)	Passed	Passed
40 units rejects datalog correlation	Passed	Passed



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Carrier Tape and Plastic Reel comparisons:

Table 1: Carrier Tape Comparisons

Parameter	IDT Penang Carrier Tape		ASEK Carrier Tape	
	PCT BGA3x7.5GP-22B3-305C-SD		Advantek CCA112-A	
Ao	3.4	± 0.1 mm	3.4	± 0.1 mm
Bo	7.9	± 0.1 mm	7.9	± 0.1 mm
Ko	1.7	± 0.1 mm	1.7	± 0.1 mm
Ki	0.9	± 0.1 mm	0.9	± 0.1 mm
P	4	± 0.1 mm	4	± 0.1 mm
W	16	± 0.3 mm	16	± 0.3 mm
Photo				

Table 2: Plastic Reel Comparisons

Parameter	IDT Penang Plastic Reel	ASEK Plastic Reel
	P9-056-000 / TAIPEX 3.3C161304(BLK)	Advantek RD33008DBK + RD33008DBK
Reel Size	13"	13"
Hub Size	4"	4"
Photo		